

<b>Search Notes</b> 	<b>Application/Control No.</b>	<b>Applicant(s)/Patent under Reexamination</b>	
	10/675,736	SHEN ET AL.	
	<b>Examiner</b>	<b>Art Unit</b>	
	A. J. HEINZ	2627	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
See			
Search		6/8/06	AH
History			